





an Open Access Journal by MDPI

# **Computer Vision and Pattern Recognition Techniques**

Collection Editor:

## Dr. Donghyeon Cho

Department of Electronics Engineering, Chungnam National University, Daejeon 34134, Republic of Korea

# **Message from the Collection Editor**

Dear Colleagues,

Recently, AI, machine learning, pattern recognition, and deep learning have been attracting attention in various fields of applications, such as autonomous driving, IoT, robot, drone, smart mobility, etc. These applications acquire data from the surrounding environment through sensing; they then analyze the acquired data, making decisions and actions based on the analysis. Vision sensors are mainly used to acquire data, thus, computer vision technology that analyzes and utilizes visual information is of great importance. The aims of this Special Issue are to provide a venue to publish various research about computer vision technologies based on Al, machine learning, pattern recognition, and deep learning. Specifically, our scope includes recognition tasks (including image classification, object detection, and segmentation), low-level vision tasks (including super resolution and image denoising), and tasks related to video and 3D vision.











an Open Access Journal by MDPI

## **Editor-in-Chief**

#### Prof. Dr. Flavio Canavero

Department of Electronics and Telecommunications, Politecnico di Torino, 10129 Torino, Italy

# **Message from the Editor-in-Chief**

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

### **Author Benefits**

**Open Access:** free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility: indexed within Scopus, SCIE (Web of Science),

CAPlus / SciFinder, Inspec, and other databases.

**Journal Rank:** JCR - Q2(*Electrical and Electronic Engineering*) CiteScore - Q2 (*Electrical and Electronic Engineering*)

### **Contact Us**